730V Super-Junction Power MOSFET

DESCRIPTION

730V super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The SJ MOSFET is a price-performance optimized product enabling to target cost sensitive applications in Consumer and Lighting markets, designed by Wuxi Unigroup Microelectronics Company.

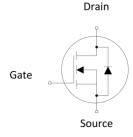
FEATURES

- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)







Device Marking and Package Information

Device	Package	Marking
TPA73R400M	TO-220F	73R400M

Key Performance Parameters

Parameter	Value	Unit
V _{DS} @ T _{j,max}	730	V
R _{DS(on),max}	0.4	Ω
I _D	11	A
$Q_{g,typ}$	20.5	nC
I _{DM}	33	A



Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	730	V
Continuous Drain Current	T _C = 25°C	l _D	11	A
Continuous Brain Current	TC = 100°C	'D	6.6	
Pulsed Drain Current	(note1)	I _{DM}	33	А
Gate-Source Voltage		V _{GSS}	±30	V
Single Pulse Avalanche Energy	(note2)	E _{AS}	215	mJ
Repetitive Avalanche Energy	(note2)	E _{AR}	0.32	mJ
Avalanche Current		I _{AR}	1.8	А
MOSFET dv/dt ruggedness, V _{DS} = 0480V		dv/dt	50	V/ns
Power Dissipation		P _D	31	W
Continuous Body Diode Current		I _S	9.4	
Pulsed Diode Forward Current (note1)		I _{SM}	33	A
Reverse diode dv/dt (note3)		dv/dt	15	V/ns
Maximum diode commutation speed (note3)		di _f /dt	500	A/us
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150	°C

Thermal Resistance				
Parameter	Symbol	Value	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	4	°C/W	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	80	30/00	



		-	Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_{D} = 250\mu A$	730			V	
Zava Cata Valtana Dunin Cumunt		$V_{DS} = 7300V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 730V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			100	μA	
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.0	V	
Drain-Source On-Resistance	R _{DS(on)}	$V_{GS} = 10V, I_{D} = 5.5A$		0.35	0.4	Ω	
Gate resistance	R _G	f = 1.0MHz open drain		18		Ω	
Dynamic	!						
Input Capacitance	C _{iss}	\/ Q\/		828		pF	
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$		33			
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		1.9			
Total Gate Charge	Q _g			20.5		nC	
Gate-Source Charge	Q_{gs}	$V_{DD} = 580V, I_{D} = 11A, V_{GS} = 10V$		5			
Gate-Drain Charge	Q_{gd}	65		9			
Turn-on Delay Time	t _{d(on)}			22			
Turn-on Rise Time	t _r	$V_{DD} = 400V, I_{D} = 11A,$		21			
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		115		ns	
Turn-off Fall Time	t _f			36			
Drain-Source Body Diode Characte	ristics						
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 11A$, $V_{GS} = 0V$		0.9	1.2	V	
Reverse Recovery Time	t _{rr}			314		ns	
Reverse Recovery Charge	Q _{rr}	$V_R = 400V, I_F = 11A,$ $di_F/dt = 100A/\mu s$		3.08		μC	
Peak Reverse Recovery Current	I _{rrm}			19.6		Α	

Notes

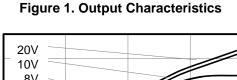
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 2.4A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. Identical low side and high side switch with identical $R_{\rm G}$

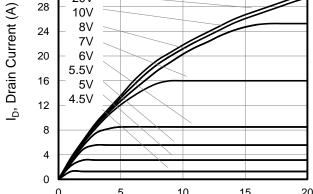
Figure 2. Transfer Characteristics

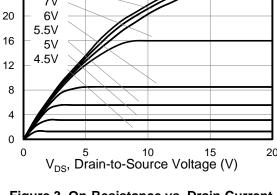


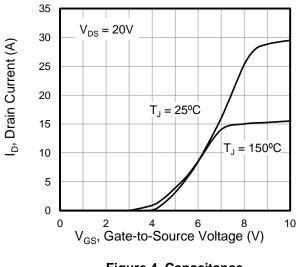
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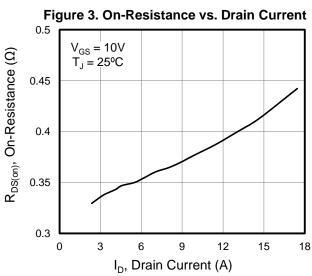
Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

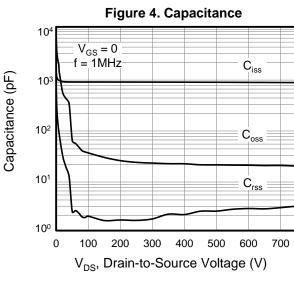


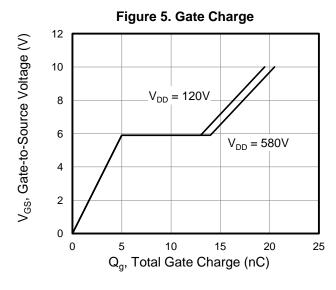


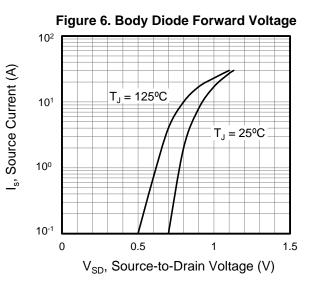














Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

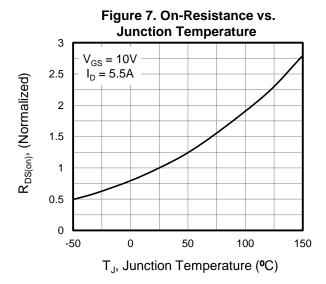


Figure 9. Transient Thermal Impedance TO-220F

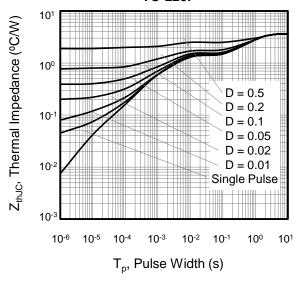


Figure 8.Breakdown voltage vs. Junction Temperature

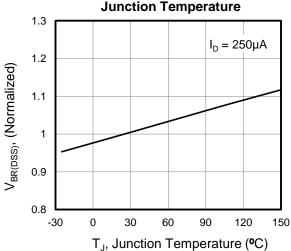


Figure 10. Safe operation area for

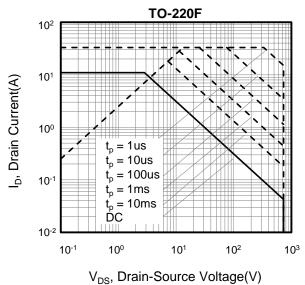


Figure A: Gate Charge Test Circuit and Waveform

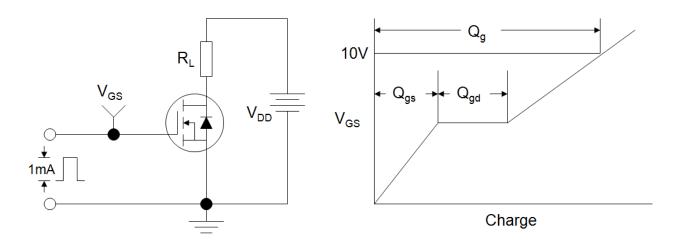


Figure B: Resistive Switching Test Circuit and Waveform

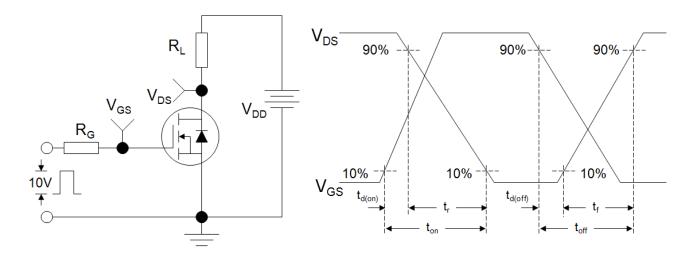
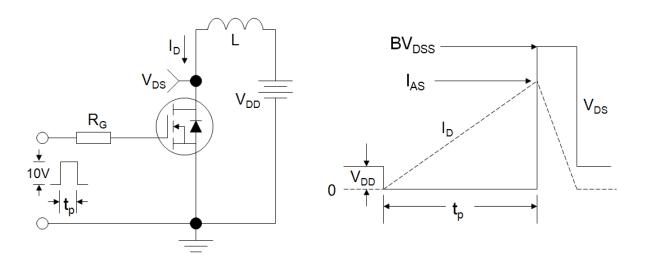
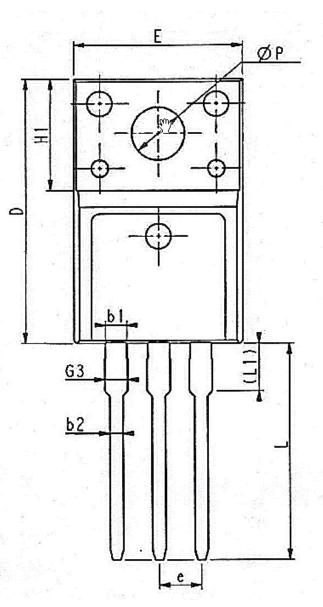


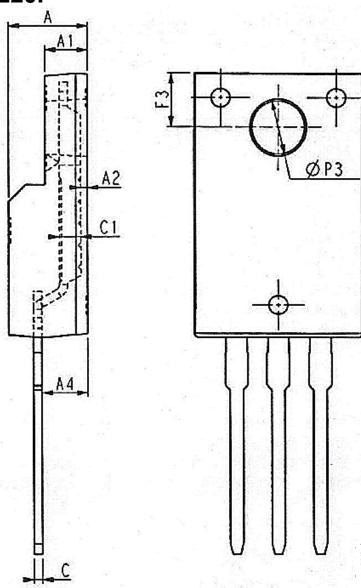
Figure C: Unclamped Inductive Switching Test Circuit and Waveform





TO-220F





Symbol	Min.	Nom	Max.	Symbol
E	9.96	10.16	10.36	е
А	4.50	4.70	4.90	L
A1	2.34	2.54	2.74	L1
A2	0.30	0.45	0.60	ФР
A4	2.56	2.76	2.96	ФР3
С	0.40	0.50	0.65	F3
c1	1.20	1.30	1.35	G3
D	15.57	15.87	16.17	b1
H1	6.70REF			b2

Unit:mm					
Symbol	Min. Nom		Max.		
е		2.54BSC			
L	12.68	12.98	13.28		
L1	2.88	3.18			
ФР	3.03	3.18	3.38		
ФР3	3.15	3.65			
F3	3.15	3.15 3.30			
G3	1.25	1.35	1.55		
b1	1.18 1.28 1.43				
b2	0.70	0.80	0.95		



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